

AD8397 Die and Data Sheet Revision

Qualification Results Summary of AD8397 Die Revision

QUALIFICATION PLAN / STATUS			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	1 x 30	Pass
Latch-Up**	JEDEC <i>JESD78</i>	N/A	N/A
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JS-001</i>	3/voltage	Pass 1000V
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	3/voltage	Pass 1250V

* Preconditioned per JEDEC/IPC J-STD-020

** AD8397 is fabricated on a dielectrically-isolated wafer fabrication process that provides inherent latch-up immunity.